**SEM - Carl Zeiss Merlin**

Scanning Electron Microscope - Carl Zeiss Merlin

- **Description**
  - The **Merlin** is a high-resolution Field-Emission Scanning Electron Microscope (FE-SEM) designed for high contrast low-voltage imaging of delicate samples with resolution better than one nanometer. The Merlin has several low-noise backscatter and secondary electron detectors, a novel charging compensation mode, and has become our primary tool for studying soft materials samples such as polymers, nanoparticles, and active biological materials such as patterned silicon nanowires.

- **Configuration**
  - High-resolution model (40nA)
  - Detectors: In-Lens, EsB, AsB, & SE2
  - 80mm Airlock
  - GIS Charge Compensator (N2)
  - IBSS GC10x Plasma Asher
  - Spiced SC-20DC

- **Training**
  - Users may request SEM training on the Merlin

- **Location**
  - SEM Lab: GCIS ESB28A

- **Contact**
  - Qiti Guo